



JFW / AF

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor:	Bryan J. Root	Examiner: Group Art Unit:	Nguyen, Tung X. 2829
Appln. No.:	10/607,768		
Filed:	June 27, 2003		
Title:	Shielded Probe Apparatus for Probing Semiconductor Wafer		

**AMENDMENT AND RESPONSE UNDER 37 C.F.R. 1.116**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

I hereby certify that this document is being sent via First Class U. S. mail addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this 8th day of September, 2005.

*Barbara A. Avery*  
Barbara A. Avery

Dear Sir:

In response to the Final Office Action of August 9, 2005 please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.